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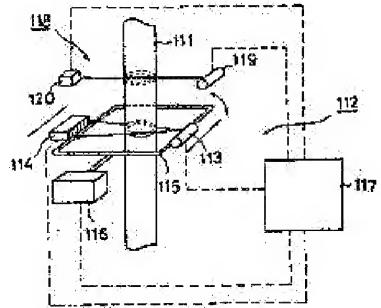
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(54) METHOD FOR MEASURING DISTRIBUTION OF LOCAL VOID RATE

(57)Abstract:

PURPOSE: To measure the distribution of a local void rate accurately, by measuring a time when projection data is converged to a constant value in advance, and performing the measurement at this timing.

CONSTITUTION: A density meter 118 for X rays or γ rays is arranged so as to hold a pipe 111, in which a sample to be checked flows. A time, when projection data is converged into a constant value, is measured in advance by the density meter 118, and a collecting time of the projection data is determined. Based on the determined collecting time, a CT scanner device 112 is actuated and the measurement is started. Namely, a driving device 116 is controlled by a control device 117, a radiation source 113, which generates X rays or γ rays, and a detector 114 are made to scan, and the distribution of a local void rate in the pipe 111 is measured. Thus the distribution of the local void rate can be measured accurately.



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